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# MECHANICAL PROPERTIES & FAILURE ANALYSIS OF CERAMIC AND GLASS MATERIALS – KEVIN STRONG

Ceramics Expo 2023

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# CERAMIC CAREER BACKGROUND

- B.S. Ceramic Engineering – Alfred University (2008)
- Post-Bachelor at Oak Ridge National Laboratory (2008-2009)
  - Mechanical testing of armor ceramics and glasses
- Ph.D. Materials Science and Engineering - University of Washington (2015)
  - Processing and Mechanical properties of  $\text{Si}_3\text{N}_4/\text{SiC}$  composites.
- Sandia National Laboratories (2015 – Present)
  - Subject Matter Expert of Ceramic and Glass Materials (focus on mechanics/mechanical properties)
  - Job Duties: Failure Analysis of ceramic and glass components (fractography), design and testing of ceramic and glass components under realistic environments, research slow crack growth phenomena / delayed failure



**Sandia  
National  
Laboratories**



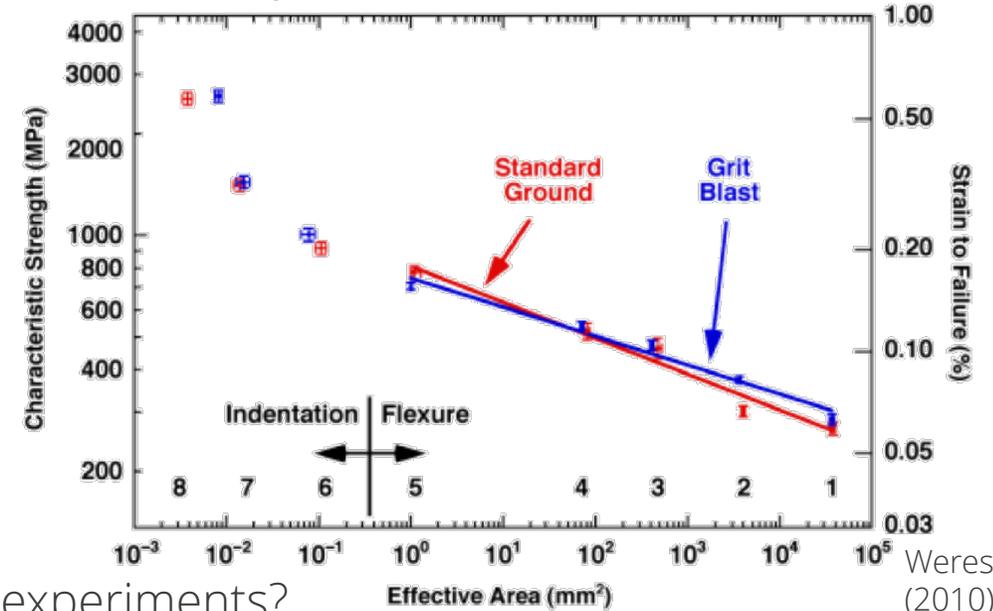
# ASSESSING STRENGTH AND RELIABILITY

Use statistical approaches (Weibull) to predict strength of ceramics parts from standard laboratory experiments.

Strength size scaling works if:

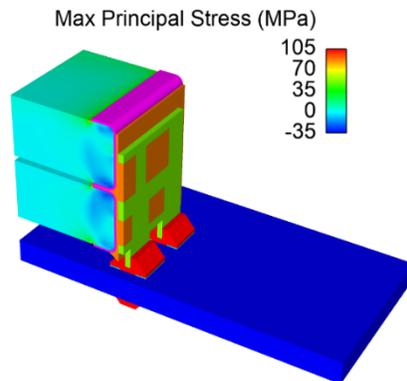
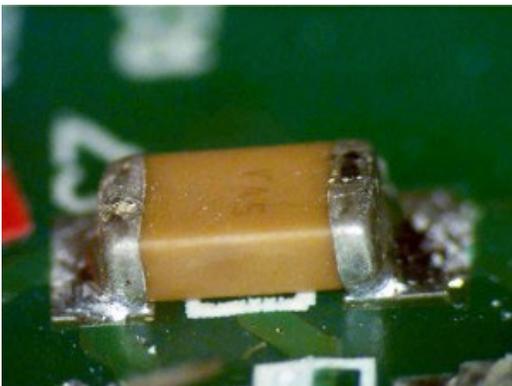
- 1) flaw size and size distribution are the same
- 2) know the applied stress and stressed area

$$P_f = 1 - \exp \left[ - \left( \frac{\sigma}{\sigma_0} \right)^m \right] \quad \sigma_B = \left( \frac{k_{AA} A_A}{k_{AB} A_B} \right)^{1/m} * \sigma_A$$

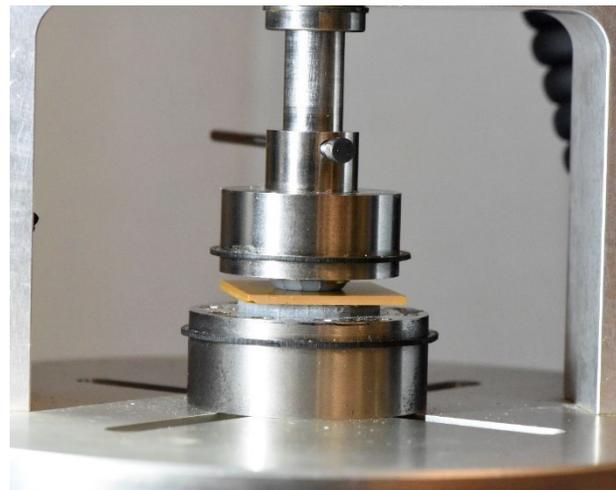


Wereszczak (2010)

How do you predict strength and reliability of real ceramic parts in components...



from laboratory experiments?

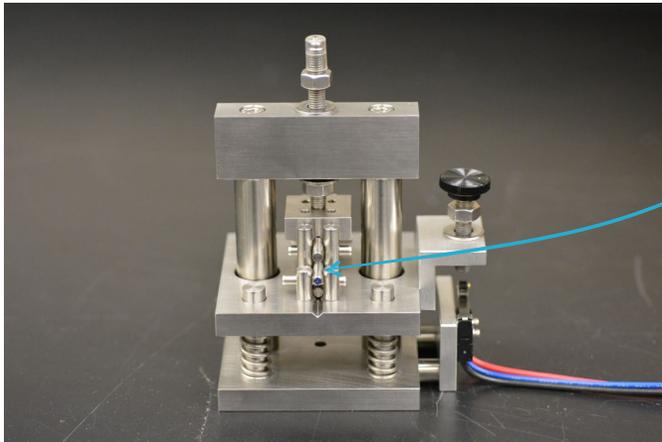




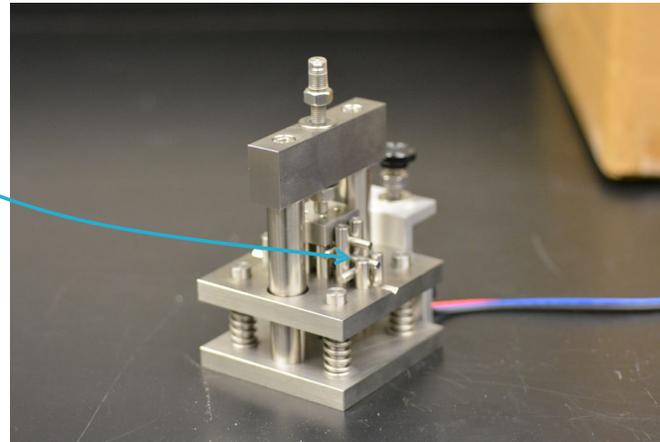
# DELAYED FAILURE PREDICTIONS

Need to account for delayed failure in ceramics for long term reliability.

## Static Fatigue Fixtures



Bend bar goes here



## Weibull Parameters

$$\sigma_0 = 186 \text{ MPa}, \rho = 4.654$$

## Slow Crack Growth Parameters

$$A = 0.00183 \text{ m/s}, n = 90.7$$

$$P_f = 1 - \exp \left( - \left\{ \frac{\left[ \frac{A(n-2)Y^2\sigma_f^2 t_f}{2K_{Ic}^2} + 1 \right]^{\frac{1}{n-2}} \sigma_f}{\sigma_0} \right\}^\rho \right)$$

## Measured Delayed Failure Times

